

In the Claims:

Please cancel claims 5, 10-12, 16, 20, 23, 49-62, 66-69, and 76-77. The claims are as follows:

1-23. (Canceled)

24. (Currently amended) ~~The method of claim 23~~ A method for increasing an electrical resistance of a resistor, comprising the steps of:

providing a predetermined target resistance in terms of a value R_t and a tolerance ΔR_t for the electrical resistance of the resistor;

providing a semiconductor structure that includes the resistor;

exposing a fraction F of an exterior surface of a surface layer of the resistor to oxygen-containing particles; and

oxidizing a portion of the surface layer by reacting said portion with said oxygen-containing particles, such that an electrical resistance of the resistor is increased, wherein an exterior surface of said portion consists essentially of the fraction F of the exterior surface of the surface layer, and

testing the resistor during the oxidizing step to determine whether the electrical resistance of the resistor is within $R_t \pm \Delta R_t$,

wherein if during the testing step the electrical resistance of the resistor is determined to not be within $R_t \pm \Delta R_t$ then the method further comprises:

iterating such that each iteration of the iterating includes additionally executing

the exposing and oxidizing steps and additionally testing the resistor during the oxidizing step to determine whether R_2'' is within $R_1 \pm \Delta R_1$, wherein R_2'' is a latest value of the electrical resistance of the resistor as determined by said testing; and

ending the iterating if R_2'' is within $R_1 \pm \Delta R_1$ or if $(R_2'' - R_1)(R_1 - R_2'') < 0$, wherein R_1 is a latest value of the determined electrical resistance of the resistor immediately prior to said testing.

25-77. (Canceled)